

**INDUSTRY STANDARD OF THE
PEOPLE'S REPUBLIC OF CHINA**

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**Method for measurement and test of parameters of 4N infrared
focal plane detector dewar assembly**

4N红钱焦平面探测器杜瓦组件参数测试方法

(English Translation)

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What this standard covers

This standard specifies the 4N infrared focal plane detector dewar assembly (hereinafter referred to as 4N components) parameter definitions, test methods and general test conditions. 4N 4N component consists of infrared focal plane array detectors and Dewar composition. 4N infrared focal plane detector is with four time delay integration (TDI) circuit infrared focal plane detector. The total number of pixels 4N months, a total of N- channel electricity. This standard applies to 4N component testing.

Document data

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